

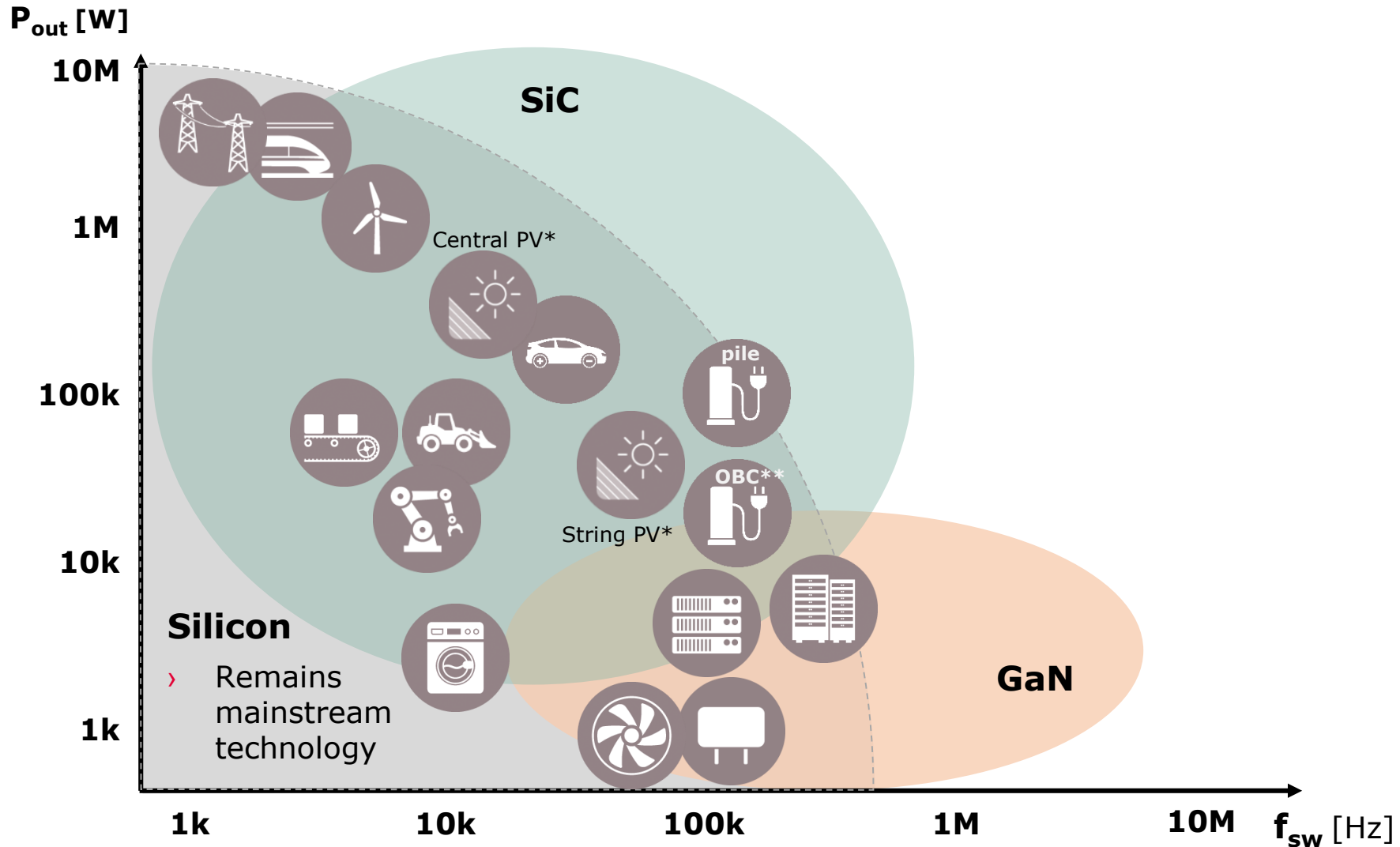
How GaN helps power supplies achieve extraordinary levels of efficiency

Eric Persson, Infineon Technologies



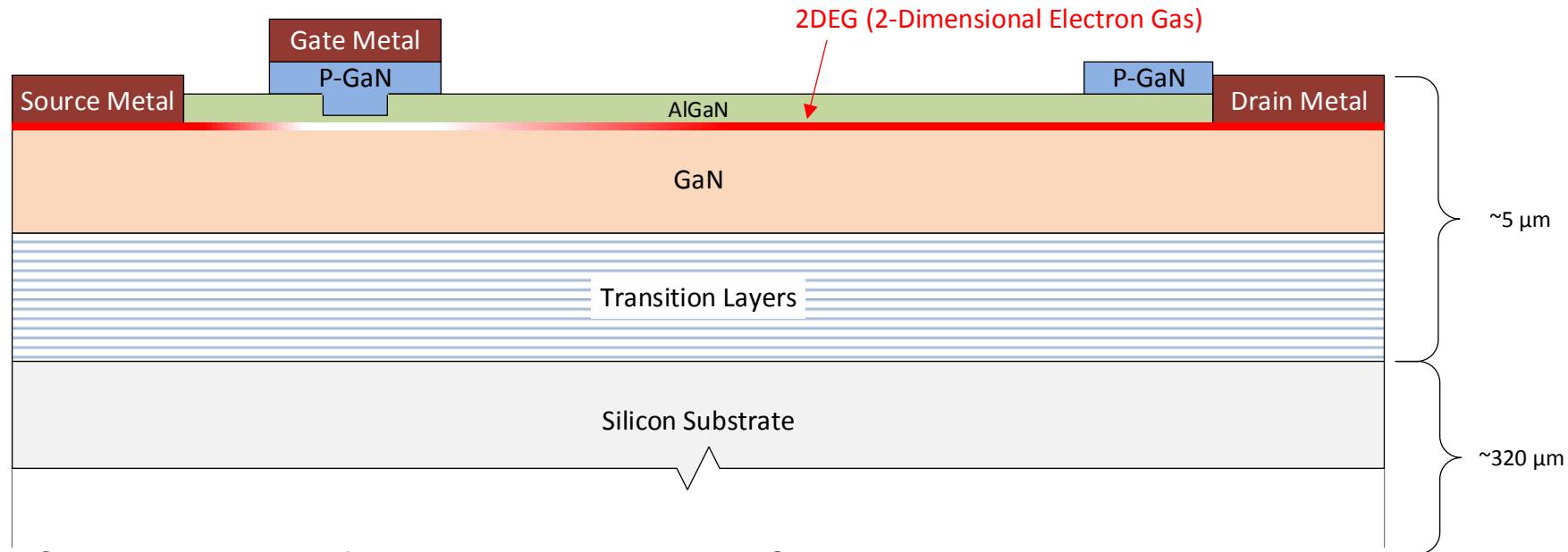
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Application map for Si, SiC, GaN



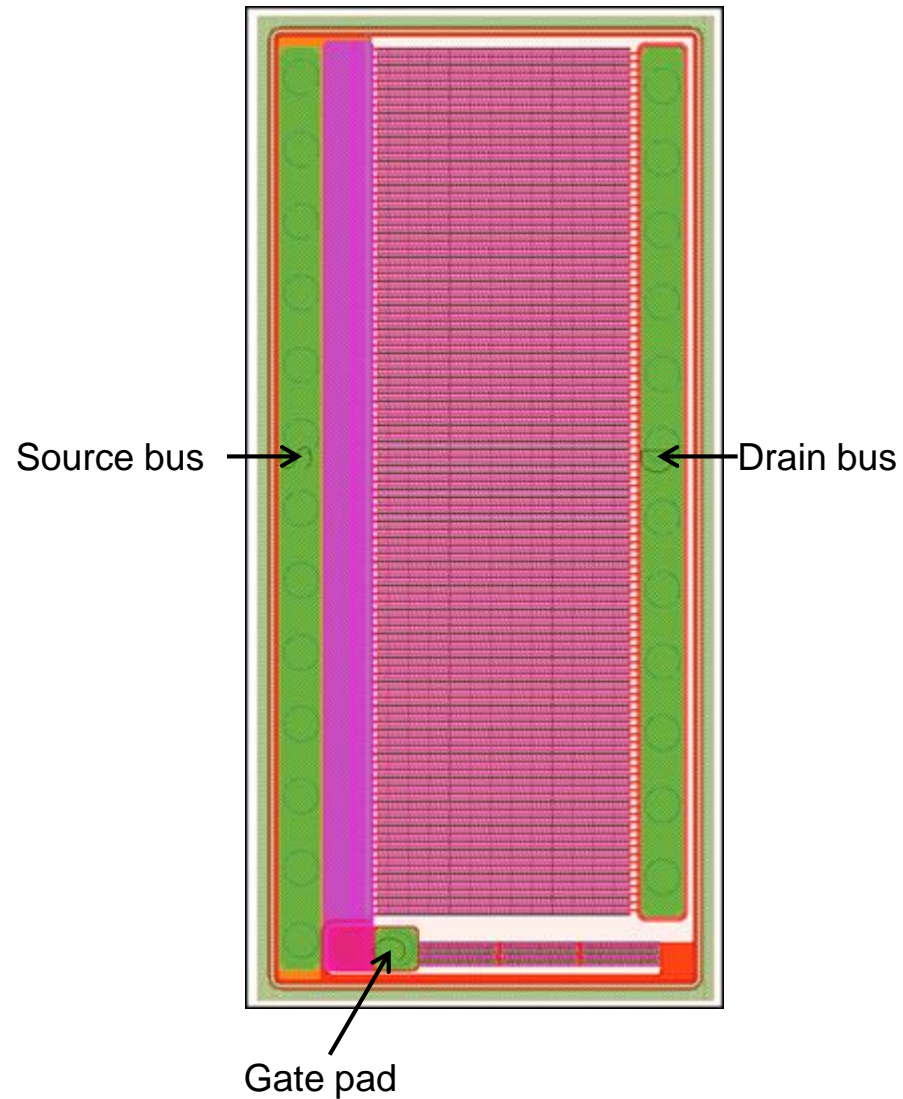
What is GaN – the technology

- GaN is a “wide-bandgap” semiconductor material that can be fabricated into high-performance power transistors
- Infineon makes devices by epitaxially growing layers of GaN (with other elements) onto Silicon substrates

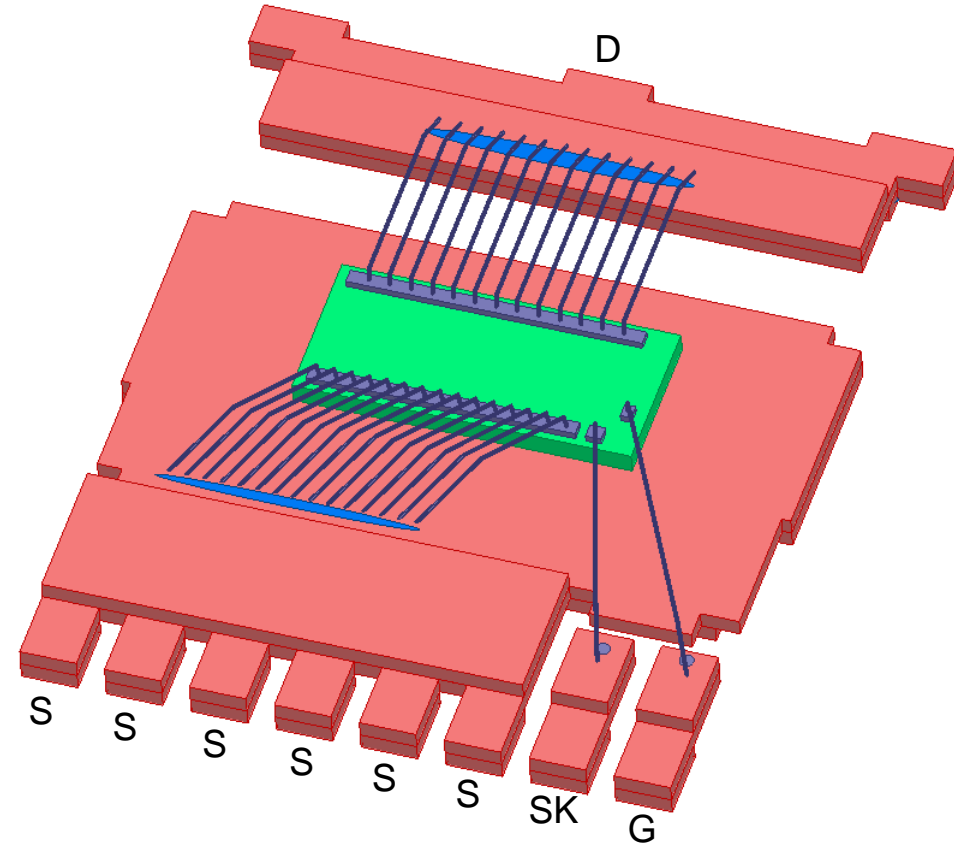


Cross-section view of 600 V Lateral *Hybrid Drain Gate Injection Transistor*.
This is an **enhancement-mode** (normally-off) device

CoolGaN™ die and package example



TO-Leadless package (TOLL) shown



Note substrate is connected to source potential:

How is CoolGaN™ better performing than Si or SiC?

The 3 key benefits of GaN transistors:

1. GaN transistors conduct in the reverse direction (third quadrant) like a diode, but there is **zero** reverse-recovery charge
 - This is a huge benefit that enables hard-switching with low-loss and low EMI
2. GaN transistor capacitance/charge is much smaller than comparable Si or SiC transistor
 - Both gate charge and output charge are lower than any competing technology – enabling fast, low-loss switching
3. Because of low charge and no minority-carriers, GaN switching speed can be very fast (single-digit ns range)
 - Especially at turn-off, the channel current can be cut-off in a few ns making turnoff losses extremely low

Comparing 600 V transistor key parameters

Parameter	CoolGaN (IGT60R070)	CoolMOS (CFD7)	SiC (SCT3060AL)	Comments
$R_{DS(on),typ}$ (m Ω)	55	57	60	Very close typical room-temp $R_{ds(on)}$ $\pm 5\%$
$Q_{rr,typ}$ (nC)	0	570	55	CoolMOS max >1000
$Q_{OSS,typ}$ @ 400 V (nC)	41	400	~60	SiC estimated from chart
$E_{OSS,typ}$ @ 400 V (μ J)	6	8	9	Relatively small differences!
t_r/t_f typ (ns)	7/10	23/6	37/21	SiC has large internal R_G
$I_{D,pulse}$ (A)	60	129	97	@25°C. GaN is 35 A @ $T_C = 125^\circ\text{C}$
R_{thJC} (MAX) °C/W	1.0	0.8	0.91	Not significant differences

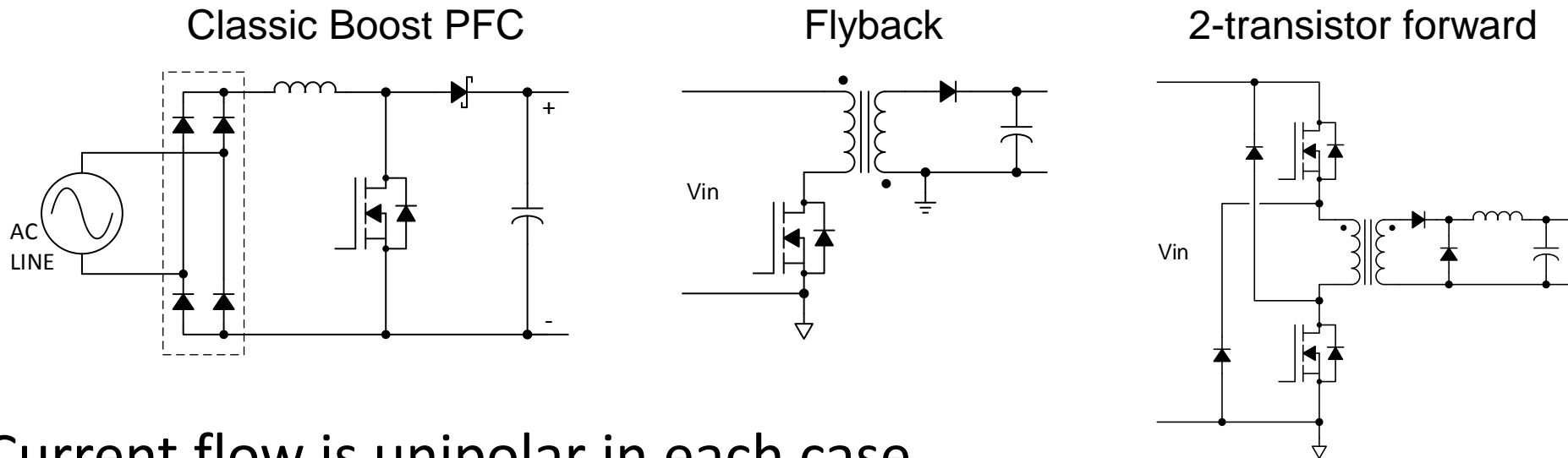
- › Note: Rohm SiC MOSFET is rated at 650 V, GaN and Si are rated at 600 V
- › CoolMOS t_f looks deceptively fast because it does not include the time spent 0-10% V_{DS} (measurement is from 10-90%)

Why are these key transistor characteristics?

- What makes these so important?
- Consider the main loss mechanisms in power transistors:
- Conduction loss: nearly the same for these 3 examples
- Switching loss – dominated by 3 factors:
 1. “crossover” loss – during the switching interval, both I_D and V_{DS} are simultaneously large creating high peak power loss
 - GaN has fastest turn-on time = lowest loss
 2. E_{OSS} – the C_{OSS} energy is dissipated during hard turn-on
 - GaN is lowest, but not by much compared to CoolMOS or SiC
 3. Reverse-recovery loss: in hard-switched half-bridge topology this can be a **huge** loss for superjunction
 - SiC is 10X better than CoolMOS, but GaN is far better than either

Benefit of GaN in single-ended topologies

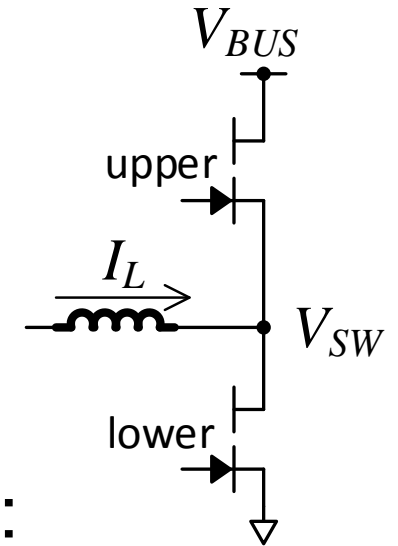
- Body-diode performance does not matter – so benefit is limited:



- Current flow is unipolar in each case
 - So body diode never conducts – its performance is irrelevant
- **CoolMOS is typically the best choice for these applications**
 - Any small improvement in switching loss using GaN is likely not worth the additional cost

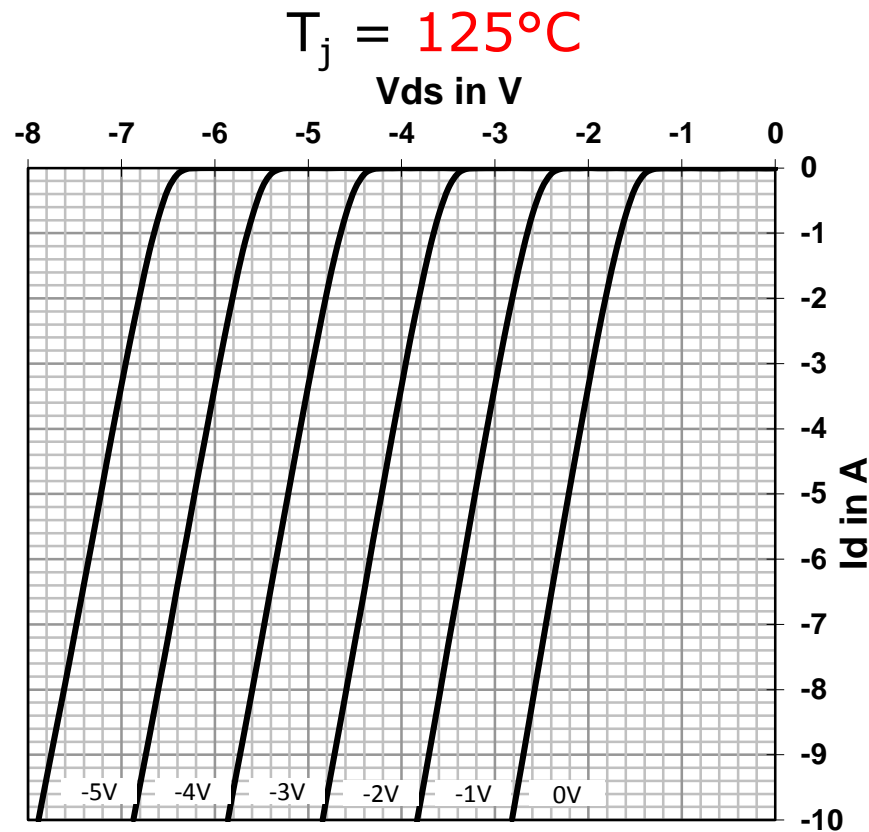
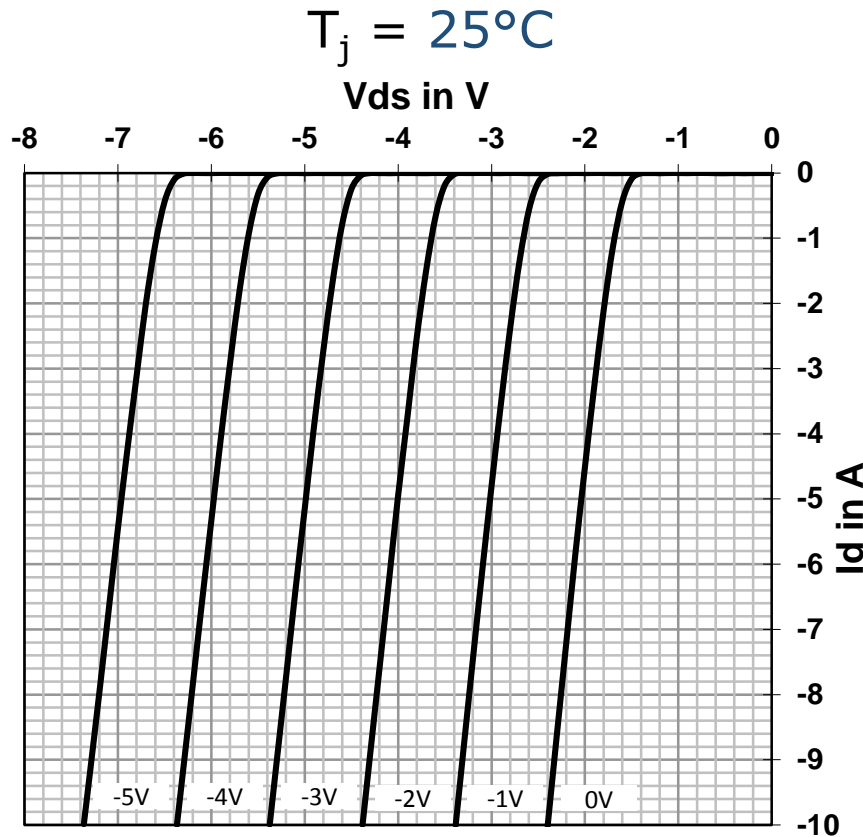
Circuits where GaN *does* provide significant benefit

- Topologies based on the half-bridge:
 - Totem-pole PFC
 - LLC converter
 - Phase-shifted bridge converter
 - Active-clamp flyback converter
 - Inverters
- The benefit provided by GaN depends on 2 key factors:
 1. Control strategy – hard or soft-switching?
 - For all hard-switching, GaN is clear choice due to zero Q_{rr}
 - For resonant/soft switching, CoolMOS for <250 kHz, GaN >250 kHz
 2. Operating frequency:
 - For Hard-switching, losses \propto frequency, so lower frequency is used for maximum efficiency
 - For soft-switching, advantage of GaN is at >250 kHz

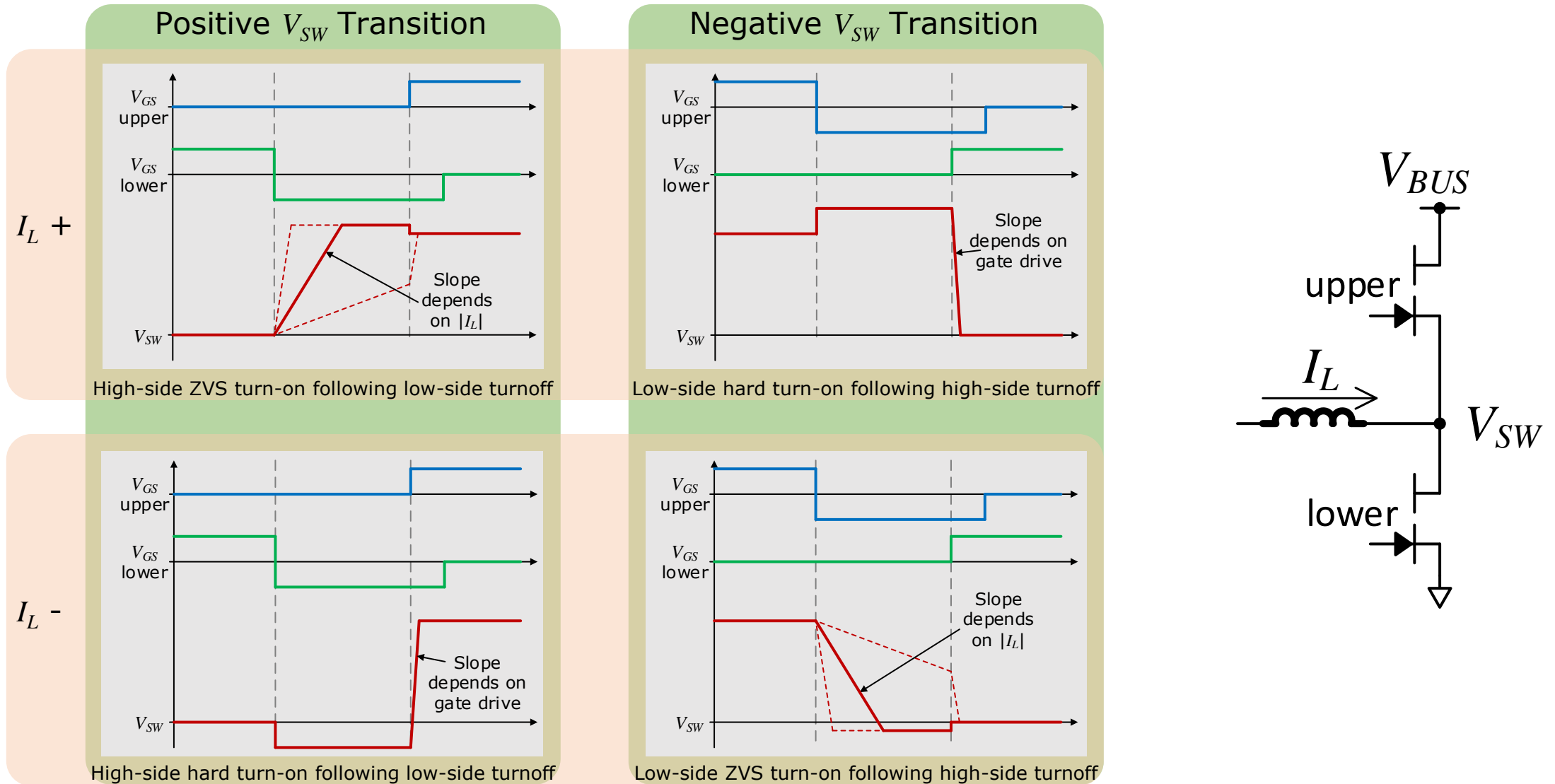


3rd quadrant conduction characteristic

- HEMT turns back ON when drain goes below G, S



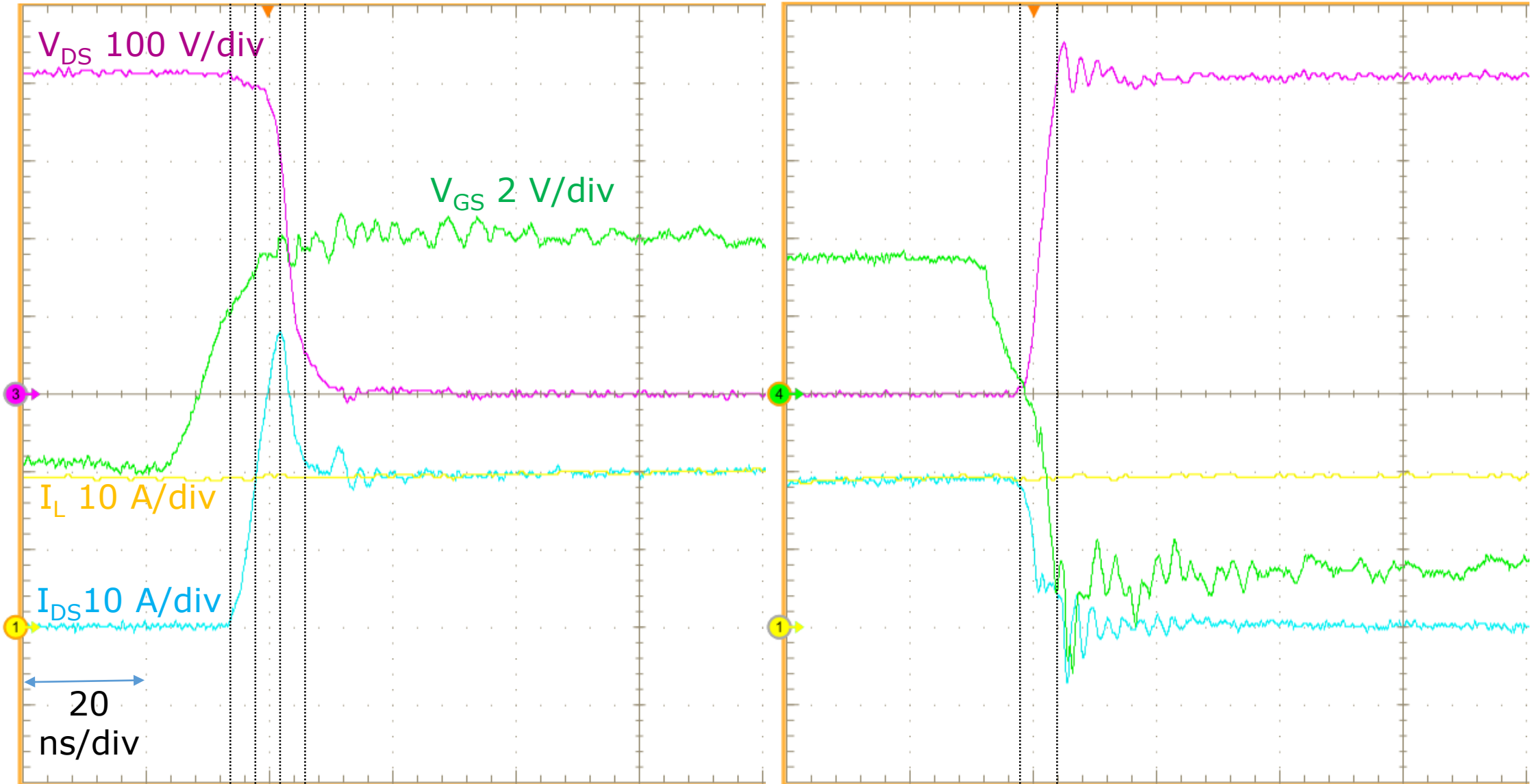
4 possible half-bridge commutation conditions



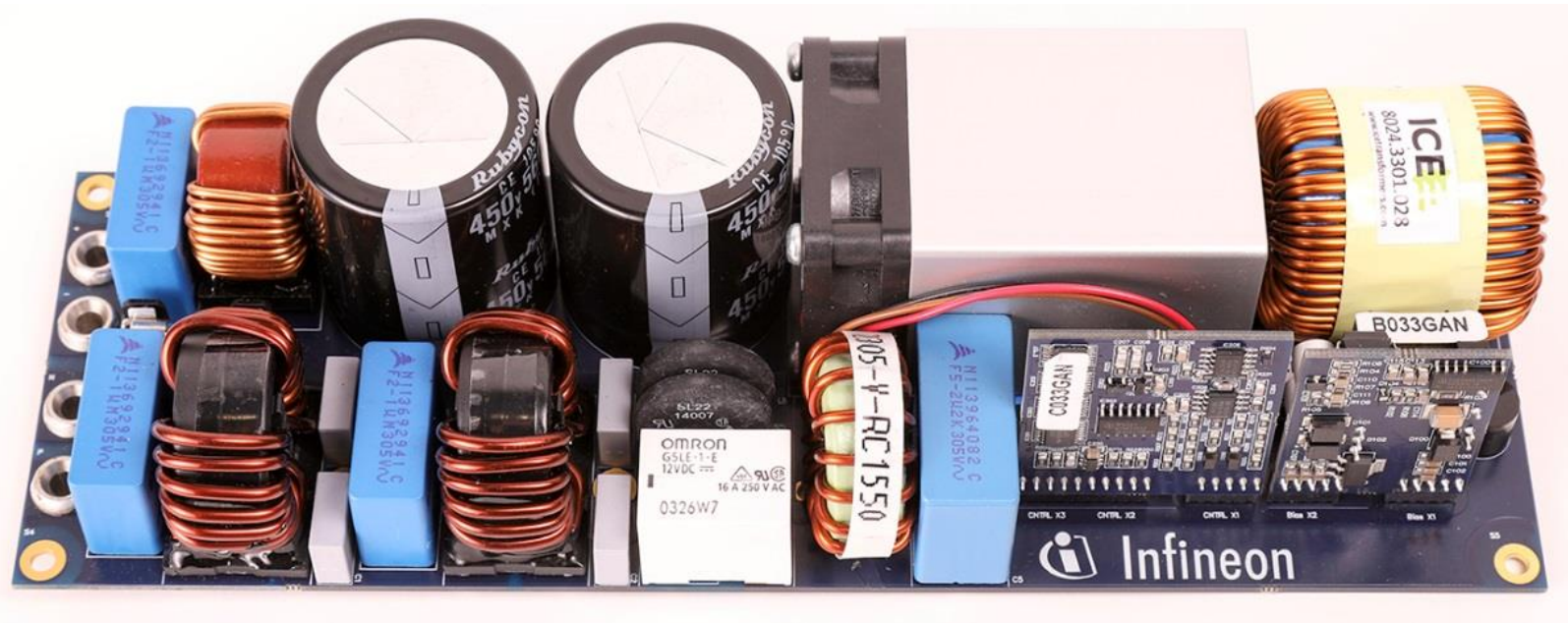
Minimizing 3rd quadrant losses

- Power dissipated in 3rd quadrant “diode mode” proportional to $V_{SD} \times I_{SD} \times \text{time} \times \text{frequency}$
- Minimize V_{SD} by using only as much negative gate drive as necessary to prevent shoot-through
- Minimize time spent in diode mode:
 - Use shortest deadtime possible, or
 - Employ adaptive deadtime optimization
 - Look-up table or calculate pulse-by-pulse

Example 20 A hard-switching waveforms

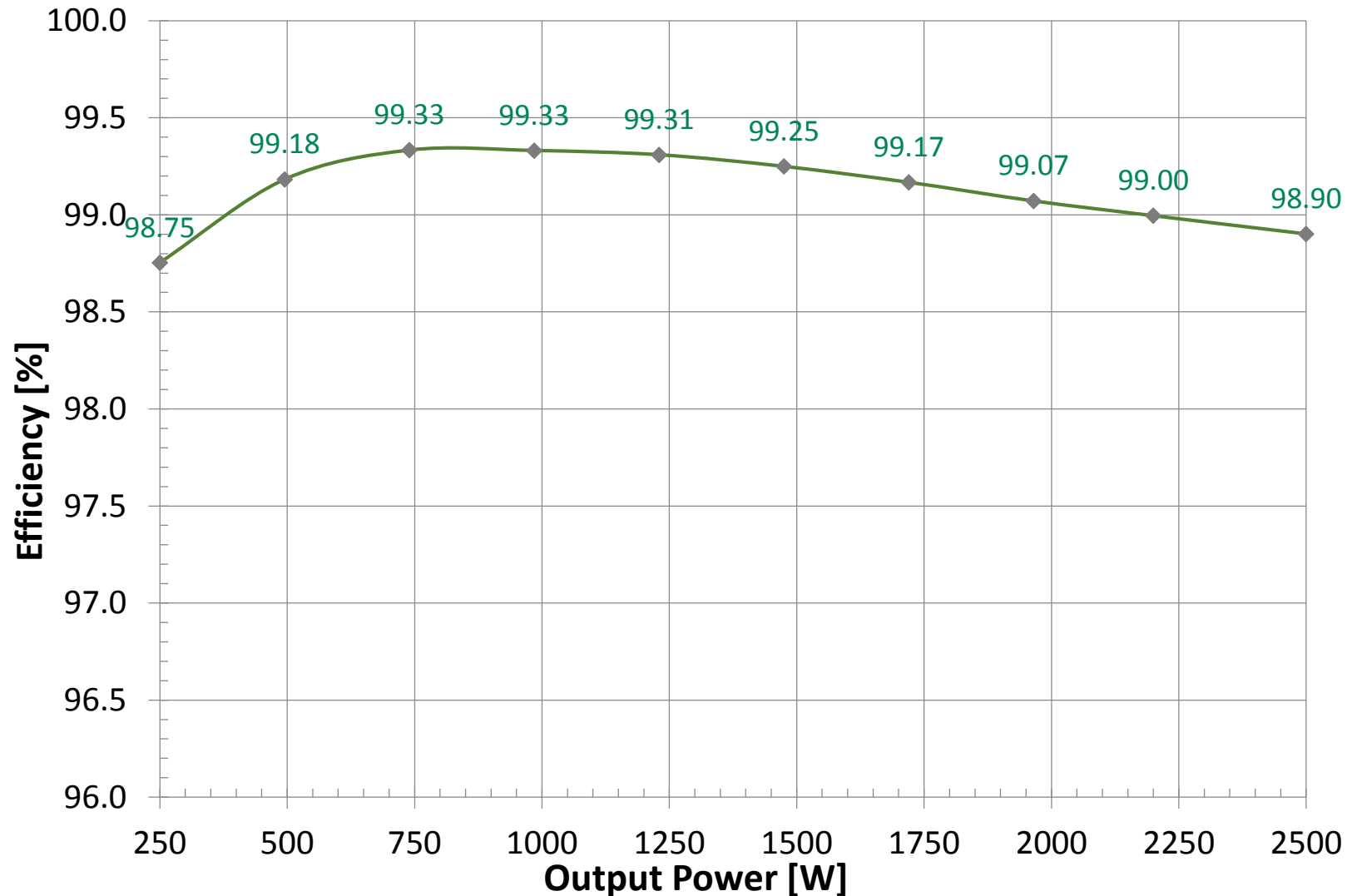


The Results:



- 2.5 kW GaN Reference Design
- CCM Full-Bridge PFC operating @ 65 kHz
- >99% efficiency over most of the load range

GaN 2.5 kW PFC measured efficiency



S/N 035 – no external power supplies – everything included. $V_{in} = 230$ V ac, $V_{out} = 390$ V dc, 25 °C Ambient

GaN 2.5 kW PFC loss breakdown

- At 1000 W output power:
 - GaN conduction loss 1.5W
 - GaN switching loss 1.1 W
 - Coolmos conduction loss 0.7 W
 - EMI filter, cap ripple loss 0.5 W
 - PFC inductor total loss 2.0 W
 - Bias supply + control circuit 1.3 W
 - (fan not running at this load)
 - Total losses ~7.1 W

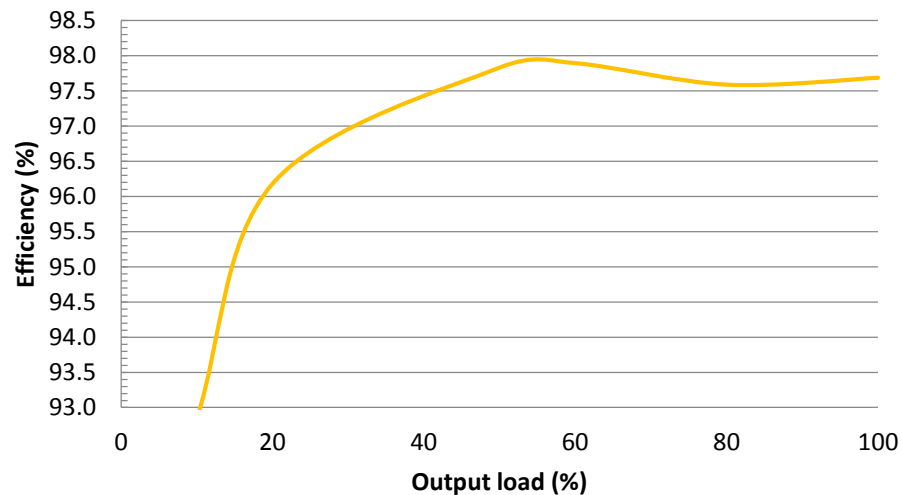
Example high-density resonant application

Main Specifications:

- › Input: 350-400 V DC, 385 V nominal
- › Output: 52 V @ 70 A, 3600 W
- › Power density: **160 W/in³**
- › LLC resonant frequency: **350 kHz**

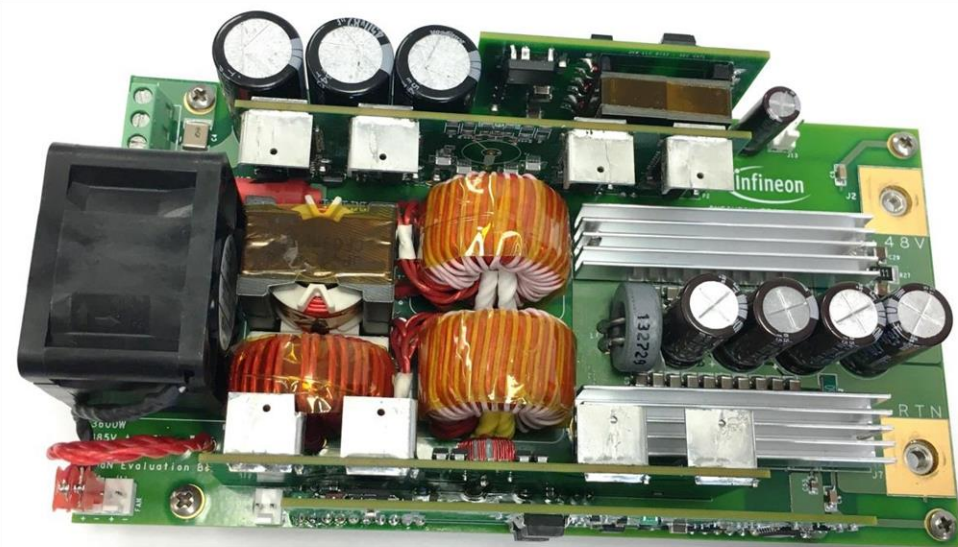
Performance:

Efficiency versus output load




Components Used:

- › CoolGaN: 70 mΩ IGT60R070D1
- › SR: 2.6 mΩ Optimos BSC026N08NS5
- › HV Driver: 1EDI20N12AF
- › LV Driver: 2EDN7524R
- › Controller: ICE2HS01G
- › Aux Supply: ICE2QR2280Z




Demoboard available


CoolGaN™ and EiceDRIVER™ in production now



CoolGaN™ 600 V




GaN EiceDRIVER™




CoolGaN™


the new power paradigm:
ultimate efficiency and reliability




- > DSO-20-87¹⁾
- > IGT60R070D1
- > 70 mΩ




- > DSO-20-85²⁾
- > IGO60R070D1
- > 70 mΩ




- > DFN 8x8
- > IGLD60R070D1
- > 70 mΩ




- > HSOF-8-3
- > IGT60R070D1
- > 70 mΩ




- > HSOF-8-3
- > IGT60R190D1S
- > 190 mΩ



- > NB DSO 16-pin³⁾
- > 150 mil
- > 1EDF5673F



- > WB DSO 16-pin⁴⁾
- > 300 mil
- > 1EDS5663H



- > 5x5 LGA 13-pin³⁾
- > 1EDF5673K

- > The most **reliable** GaN solution delivering **highest performance** amongst all available GaN devices
- > **Manufacturing expertise** throughout the entire supply chain
- > Global application design **support**
- > Broad **portfolio** including drivers
- > **Volume** capability
- > Attractive **price** projection

1) Top-side cooling 2) Bottom-side cooling 3) Functional isolation
4) Reinforced (safe) isolation

Summary

- 3 key features of GaN transistors enable high performance:
 - Zero reverse-recovery charge
 - Lower charge than competing technologies
 - Capable of faster switching
- These features are of particular benefit to half-bridge topologies
 - Lowest loss in hard-switching applications
 - Lowest rms current in soft-switching and resonant applications
- CoolGaN can be driven by off-the-shelf gate drivers
- In production and available now
- (See production power supply example in session IS16.5)